MgB₂ for SRF Cavities

Tsuyoshi Tajima Los Alamos Neutron Science Center Los Alamos National Laboratory

LA-UR-05-5049rev

Why do we need to look for new SC materials for RF cavities?

•High-purity Nb and cavities are still expensive.

•Refrigeration to get to 4 K or lower is expensive

•Nb cavities have reached close to its theoretical limit and the recipe to get good results such as $E_{acc} > 35$ MV/m repeatedly will be established within ~5 years.



Magnesium Diboride (MgB₂)

 MgB₂ was discovered to be superconductive at ~40 K in early 2001. It was a surprise since it is a simple binary intermetallic compound.

Magnesium Diboride (MgB₂)



Graphite-type boron layers separated by hexagonal closepacked layers of magnesium

Superconductivity comes from the phononmediated Cooper pair production similar to the low-temperature superconductors except for the two-gap nature.

Compared to cuprates:

- Cheaper
- Lower anisotropy
- Larger coherence length
- Transparency of grain boundaries to current flows

These makes MgB₂ attractive for applications.

C. Buzea and T. Yamashita, Superconductor Sci. Technol. 14 (2001) R115.

Developments in the past 2 years

- In 2003, R_s lower than Nb at 4 K was demonstrated with a ~400 nm film. An order of magnitude lower BCS R_s is predicted.
- A preliminary test showed little increase of R_s up to H_{RF}~120 Oe (limited by available power), i.e., equivalent of E_{acc}~3 MV/m. Encouraging.

Simple binary compound, but needs high Mg pressure to form MgB₂ phase



MgB₂ Film Growth, an example at the Superconductor Technologies, Inc. (STI)



B.H. Moeckly, ONR Superconducting Electronics Program Review Red Bank, NJ, February 8, 2005 LA-UR-05-5049rev TFSRF 2005, JLAB, July 17-18, 2005

MgB₂ on 4" substrates

R-plane sapphire

Si₃N₄ / Si



B.H. Moeckly, ONR Superconducting Electronics Program Review Red Bank, NJ, February 8, 2005 LA-UR-05-5049rev TFSRF 2005, JLAB, July 17-18, 2005

Surface morphology – MgB₂ on *r*-plane sapphire



- Typical surface on *r*-plane sapphire
- Growth $T = 550 \,^{\circ}\text{C}$
- *t* = 5500 Å
- Small, conical grains
- ~1000 2000 Å diameter
- RMS roughness = 44 Å

B.H. Moeckly, ONR Superconducting Electronics Program Review Red Bank, NJ, February 8, 2005

Surface morphology – smoother films



- B.H. Moeckly, ONR Superconducting Electronics Program Review Red Bank, NJ, February 8, 2005
- MgB₂ on MgO

•Growth *T* = 550 °C

- *t* = 3000 Å
- RMS roughness = 22 Å
- LA-UR-05-5049rev

- MgB2 on sapphire
- •Low T growth: 450 °C
- *t* = 1500 Å
- RMS roughness = 12 Å



Microstructure – MgB₂ on *c*-plane sapphire

- Columnar growth
- Clear layer at interface
- Layer looks grown, not reacted

- Grain size ~100 nm
- Numerous threading defects in lower half
- Defects decrease with thickness



B.H. Moeckly, ONR Superconducting Electronics Program Review Red Bank, NJ, February 8, 2005

Dave Smith

LA-UR-05-5049rev

Stability – DI water soak

- Films etch very slowly in water
- Films also seem stable with time

B.H. Moeckly, ONR Superconducting Electronics Program Review Red Bank, NJ, February 8, 2005

LA-UR-05-5049rev



Latest films have shown R_s lower then Nb at 4 K.

Residual resistance still dominates at lower temperatures.

1 cm² sample on r-cut sapphire



- A.T. Findikoglu et al., NSF/DOE Workshop on RF Superconductivity, Bethesda, MD, Aug. 29, 2003. B.H. Moeckly et al., IEEE Trans. Appl. Supercond. 15 (2005) 3308.
- T. Tajima et al., Proc. PAC05.

LA-UR-05-5049rev TFSRF 2005, JLAB, July 17-18, 2005

Predicted BCS R_s is ~1/10 of Nb

Dotted lines are predicted BCS resistance.



A.T. Findikoglu et al., NSF/DOE Workshop on RF Superconductivity, Bethesda, MD, Aug. 29, 2003. B.H. Moeckly et al., IEEE Trans. Appl. Supercond. 15 (2005) 3308.

LA-UR-05-5049rev

Power Dependence Tests at Cornell with 6-GHz Nb TE₀₁₁ Cavity



~400 nm film was grown on 1.5 cm Nb at STI. First attempt to coat on a Nb substrate. The Nb substrate was

rough ($R_a \sim 400$ nm).



Measurement by Alexander Romanenko, Hasan Padamsee

$R_{\rm s}$ does not change much with $H_{\rm RF}$.



Measurement at Cornell with TE_{011} Nb cavity at 4.2 K.

There was only one test and the result needs to be confirmed with others.

An idea of coating a cavity with PLD



T. Tajima et al., PAC05, Knoxville, TN, May 16-20, 2005.

KrF Excimer laser or FEL??

LA-UR-05-5049rev

Participants in this R&D (informal)

- Present
- A. Findikoglu, A. Jason, F. Krawczyk, F. Mueller, A. Shapiro (LANL)
- H. Padamsee, A. Romanenko, R. Geng (Cornell) TE cavity measurements
- B. Moeckly (STI)
- H. Abe (NIMS, Japan) Electroplating
- Y. Zhao (Univ. Wollongong, Australia) PLD
- Future
- L. Phillips, A-M, Valente, G. Wu (JLab) TE cavity measurements, coating with FEL??
- I. Campisi/S. Tantawi (SNS/SLAC) Crititcal H measurements



A. Floris et al., cond-mat/0408688v1 31 Aug 2004